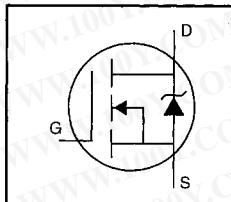


- Isolated Package
- High Voltage Isolation= 2.5KVRMS ⑤
- Sink to Lead Creepage Dist.= 4.8mm
- Dynamic dv/dt Rating
- Low Thermal Resistance



$V_{DSS} = 400V$

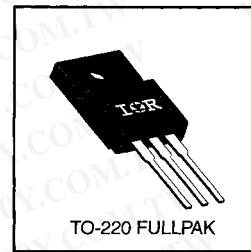
$R_{DS(on)} = 0.55\Omega$

$I_D = 5.4A$

### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.



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### Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	5.4	
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	3.4	A
$I_{DM}$	Pulsed Drain Current ①	22	
$P_D @ T_C = 25^\circ C$	Power Dissipation	40	W
$V_{GS}$	Linear Derating Factor	0.32	W/ $^{\circ}C$
$E_{AS}$	Gate-to-Source Voltage	$\pm 20$	V
$I_{AR}$	Single Pulse Avalanche Energy ②	390	mJ
$E_{AR}$	Avalanche Current ①	5.4	A
$dV/dt$	Repetitive Avalanche Energy ①	4.0	mJ
$T_J$	Peak Diode Recovery $dV/dt$ ③	4.0	V/ns
$T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^{\circ}C$
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf-in (1.1 N·m)	

### Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{JJC}$	Junction-to-Case	—	—	3.1	$^{\circ}C/W$
$R_{JJA}$	Junction-to-Ambient	—	—	65	$^{\circ}C/W$

**Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	400	—	—	V	$V_{GS}=0\text{V}$ , $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.49	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	0.55	$\Omega$	$V_{GS}=10\text{V}$ , $I_D = 3.2\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS}=V_{GS}$ , $I_D = 250\mu\text{A}$
$g_s$	Forward Transconductance	3.6	—	—	S	$V_{DS}=50\text{V}$ , $I_D = 3.2\text{A}$ ④
$I_{DS}$	Drain-to-Source Leakage Current	—	—	25	$\mu\text{A}$	$V_{DS}=400\text{V}$ , $V_{GS}=0\text{V}$
		—	—	250		$V_{DS}=320\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=125^\circ\text{C}$
$I_{GS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS}=20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS}=-20\text{V}$
$Q_g$	Total Gate Charge	—	—	66		$I_D=10\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	—	10	nC	$V_{DS}=320\text{V}$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	33		$V_{GS}=10\text{V}$ See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	14	—		$V_{DD}=200\text{V}$
$t_r$	Rise Time	—	25	—		$I_D=10\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	54	—		$R_G=9.1\Omega$
$t_f$	Fall Time	—	24	—		$R_D=20\Omega$ See Figure 10 ④
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{iss}$	Input Capacitance	—	1200	—	pF	$V_{GS}=0\text{V}$
$C_{oss}$	Output Capacitance	—	230	—		$V_{DS}=25\text{V}$
$C_{rss}$	Reverse Transfer Capacitance	—	48	—		$f=1.0\text{MHz}$ See Figure 5
$C$	Drain to Sink Capacitance	—	12	—	pF	$f=1.0\text{MHz}$

**Source-Drain Ratings and Characteristics**

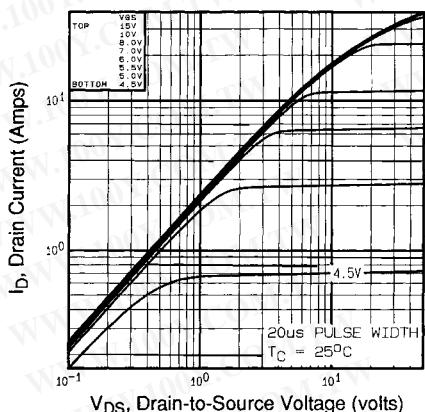
	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	5.4		MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	22	A	
$V_{SD}$	Diode Forward Voltage	—	—	2.0	V	$T_J=25^\circ\text{C}$ , $I_S=5.4\text{A}$ , $V_{GS}=0\text{V}$ ④
$t_{rr}$	Reverse Recovery Time	—	330	730	ns	$T_J=25^\circ\text{C}$ , $I_F=10\text{A}$
$Q_{rr}$	Reverse Recovery Charge	—	2.8	6.6	$\mu\text{C}$	$dI/dt=100\text{A}/\mu\text{s}$ ④
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

Notes:

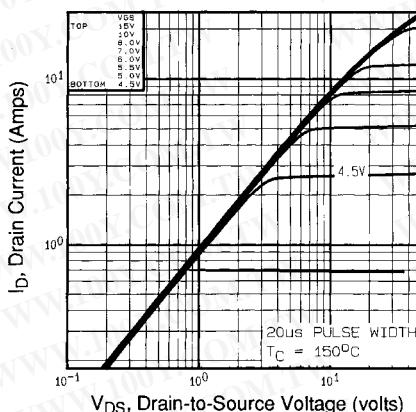
① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)

③  $I_{SD}\leq 10\text{A}$ ,  $di/dt\leq 120\text{A}/\mu\text{s}$ ,  $V_{DD}\leq V_{(\text{BR})\text{DSS}}$ ,  $T_J\leq 150^\circ\text{C}$ ⑤  $t=60\text{s}$ ,  $f=60\text{Hz}$ ②  $V_{DD}=50\text{V}$ , starting  $T_J=25^\circ\text{C}$ ,  $L=23\text{mH}$   
 $R_G=25\Omega$ ,  $I_{AS}=5.4\text{A}$  (See Figure 12)④ Pulse width  $\leq 300\ \mu\text{s}$ ; duty cycle  $\leq 2\%$ .

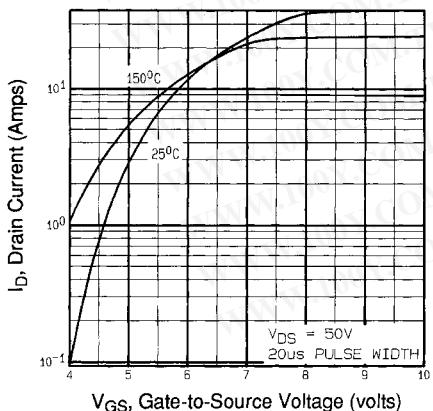
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 勝特力电子(上海) 86-21-54151736  
 勝特力电子(深圳) 86-755-83298787  
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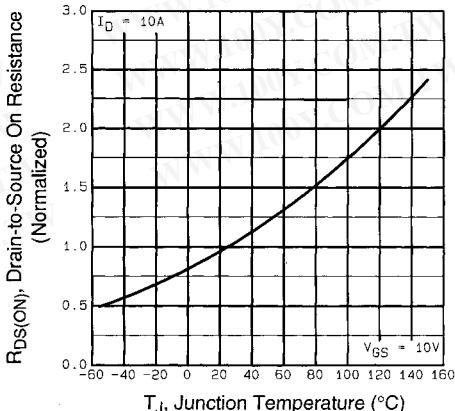
**Fig 1.** Typical Output Characteristics,  
 $T_C = 25^\circ\text{C}$



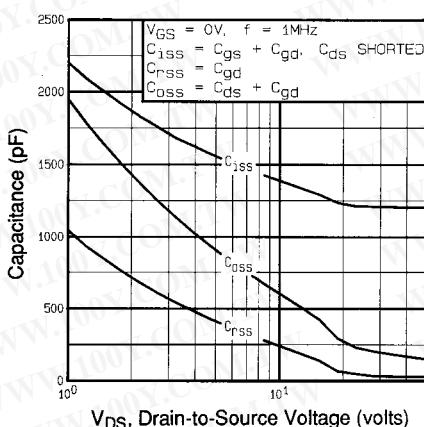
**Fig 2.** Typical Output Characteristics,  
 $T_C = 150^\circ\text{C}$



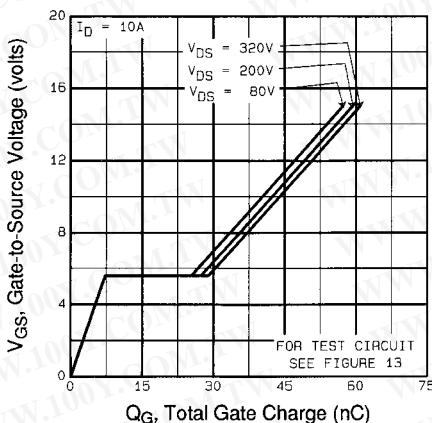
**Fig 3.** Typical Transfer Characteristics



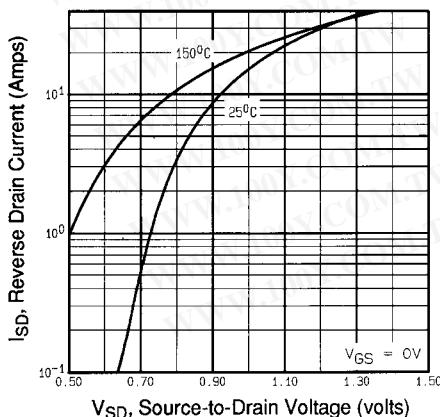
**Fig 4.** Normalized On-Resistance  
 Vs. Temperature



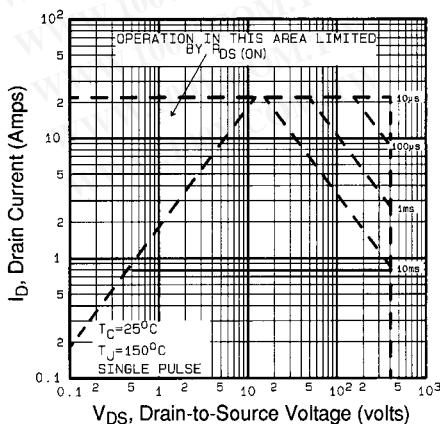
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



**Fig 8.** Maximum Safe Operating Area

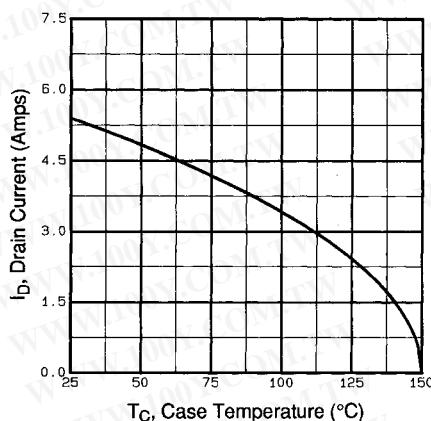


Fig 9. Maximum Drain Current Vs. Case Temperature

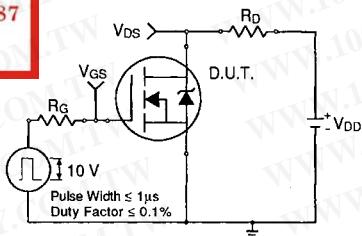
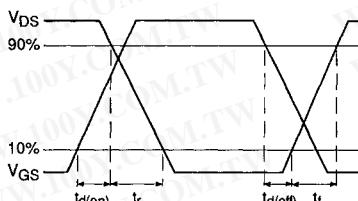


Fig 10a. Switching Time Test Circuit



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Fig 10b. Switching Time Waveforms

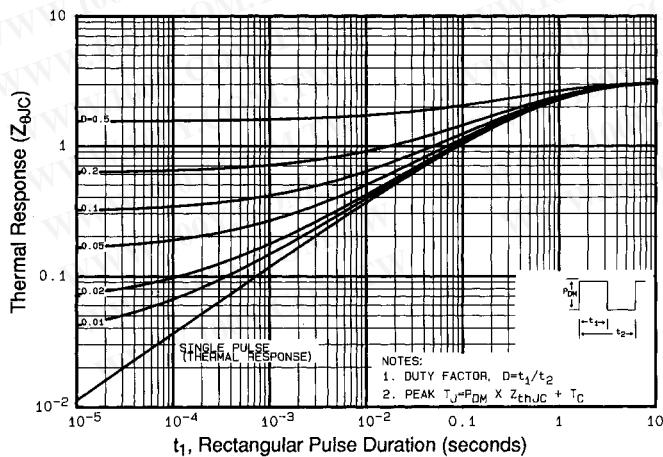
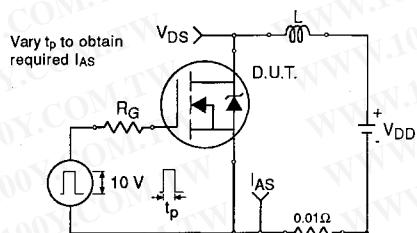
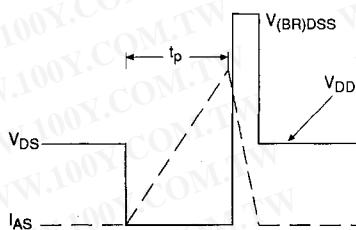


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

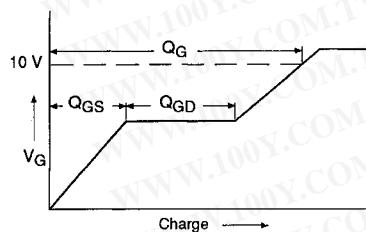
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**Fig 12a.** Unclamped Inductive Test Circuit



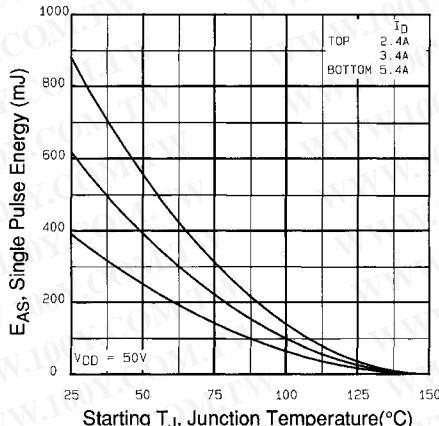
**Fig 12b.** Unclamped Inductive Waveforms



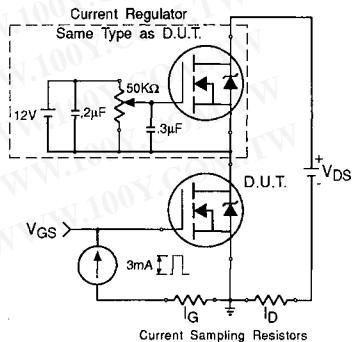
**Fig 13a.** Basic Gate Charge Waveform

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**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 13b.** Gate Charge Test Circuit

**Appendix A:** Figure 14, Peak Diode Recovery dv/dt Test Circuit – See page 1505

**Appendix B:** Package Outline Mechanical Drawing – See page 1510

**Appendix C:** Part Marking Information – See page 1517

**International Rectifier**